

FIG. 1 is a schematic diagram of a prior art device 20 for measuring the thickness of a material 27. The device 20 includes a base 66, a support 68, and a frame 70. A first transducer 64 is mounted to the base 66, and a second transducer 64 is mounted to the support 68. A first probe 30 is mounted to the frame 70, and a second probe 32 is mounted to the support 68. The first probe 30 is positioned to measure the thickness of the material 27, and the second probe 32 is positioned to measure the thickness of the material 27. The device 20 is shown in a cross-sectional view, and the material 27 is shown as a wavy line. The frame 70 is shown as a rectangular block, and the support 68 is shown as a rectangular block. The base 66 is shown as a rectangular block. The first transducer 64 is shown as a rectangular block, and the second transducer 64 is shown as a rectangular block. The first probe 30 is shown as a rectangular block, and the second probe 32 is shown as a rectangular block. The device 20 is shown in a cross-sectional view, and the material 27 is shown as a wavy line. The frame 70 is shown as a rectangular block, and the support 68 is shown as a rectangular block. The base 66 is shown as a rectangular block. The first transducer 64 is shown as a rectangular block, and the second transducer 64 is shown as a rectangular block. The first probe 30 is shown as a rectangular block, and the second probe 32 is shown as a rectangular block.

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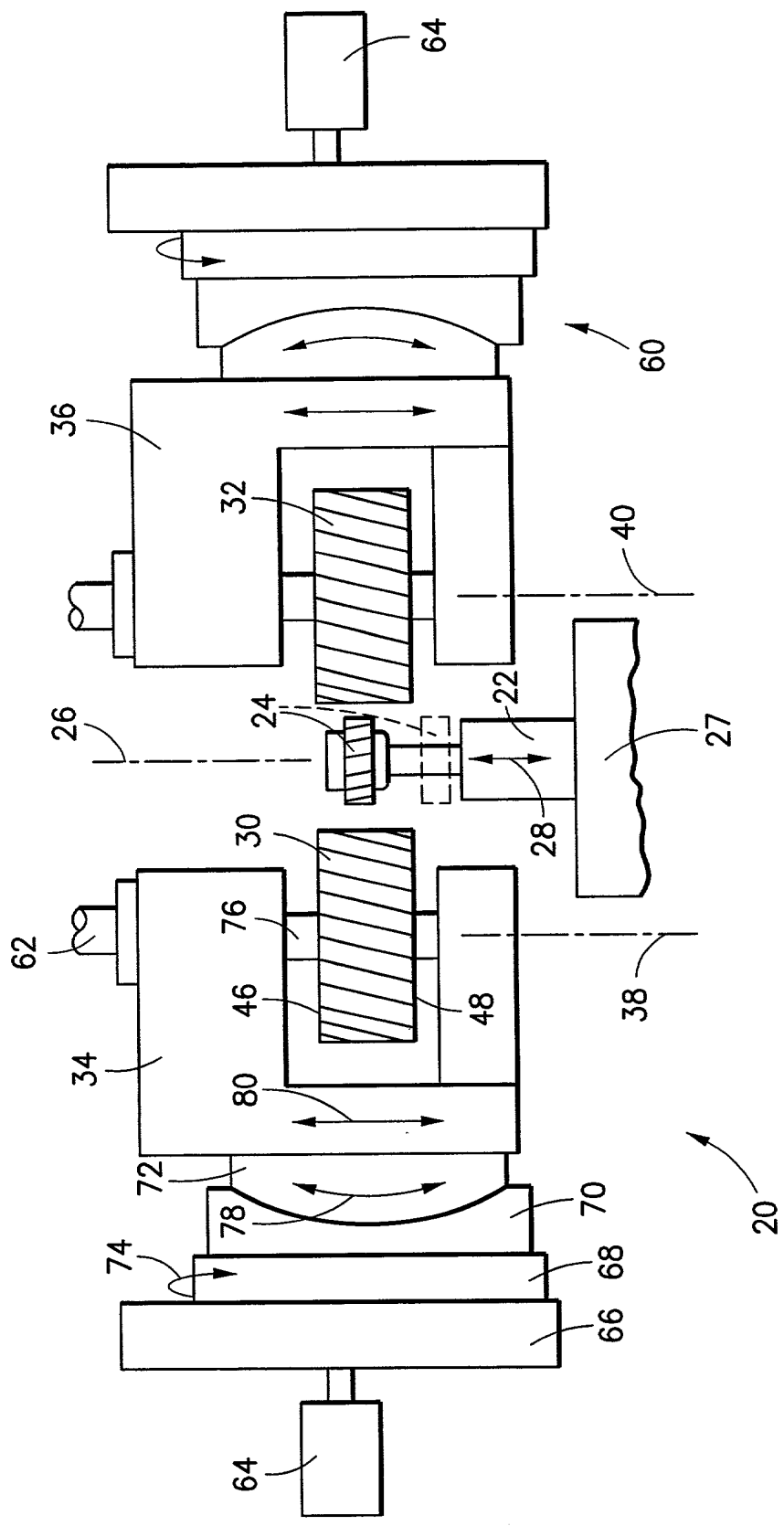


FIG.1
PRIOR ART

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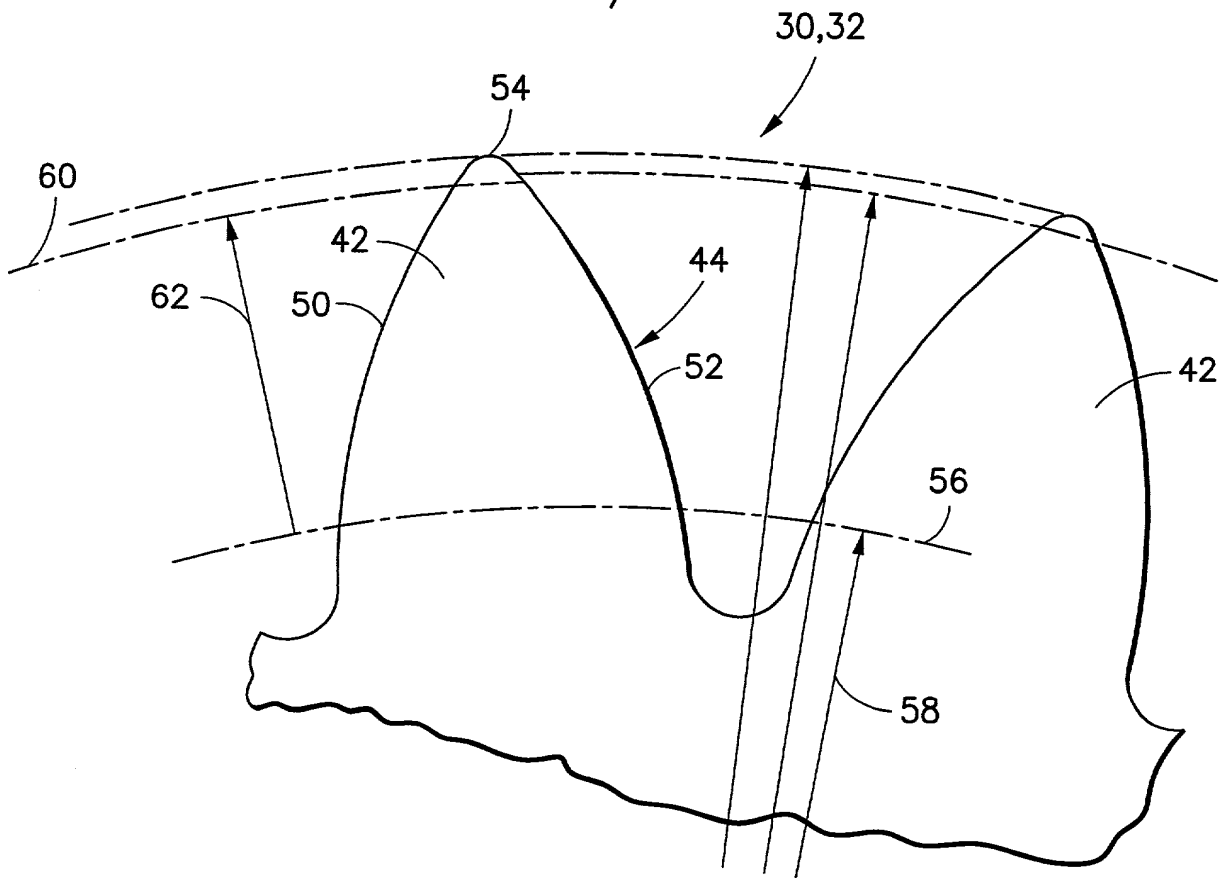


FIG. 2

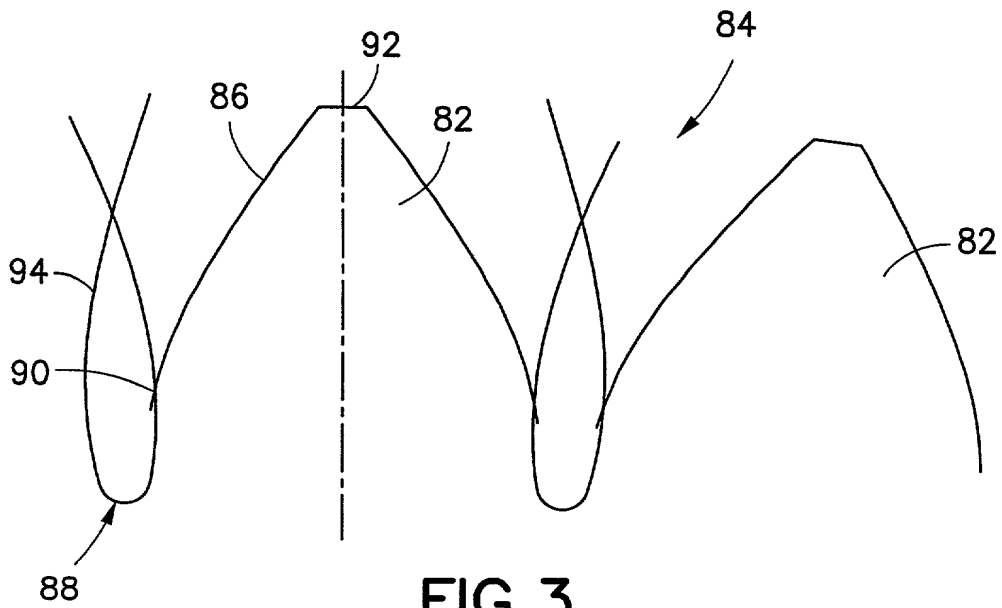


FIG. 3

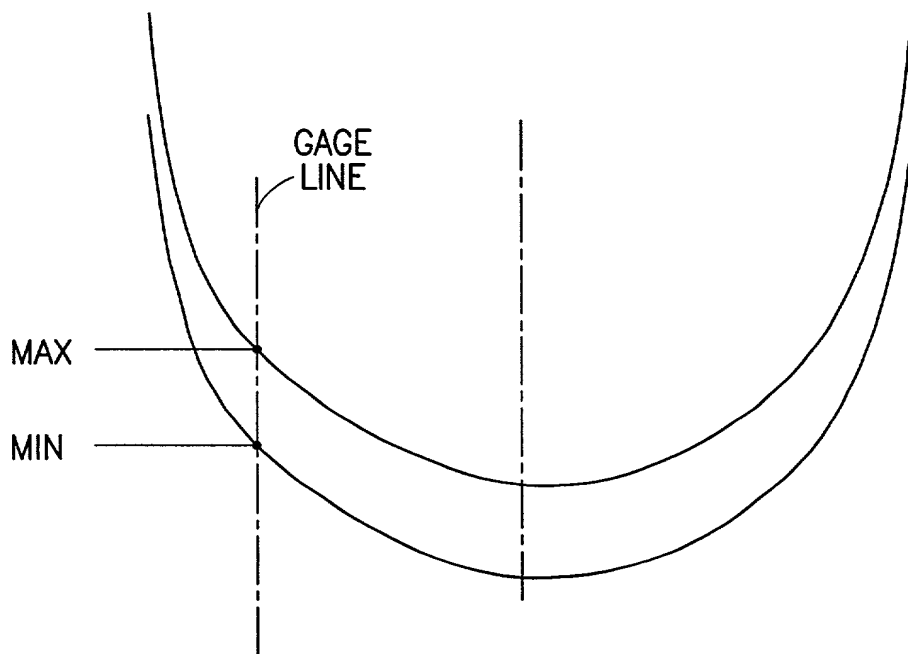


FIG. 4

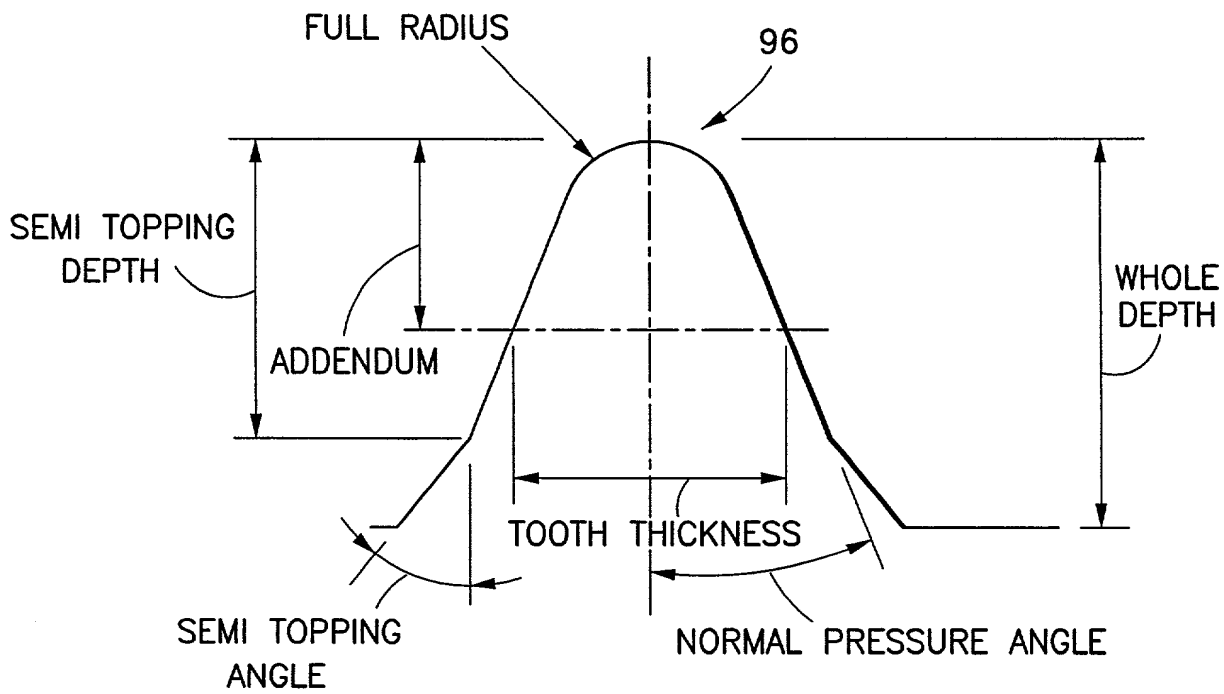


FIG. 5

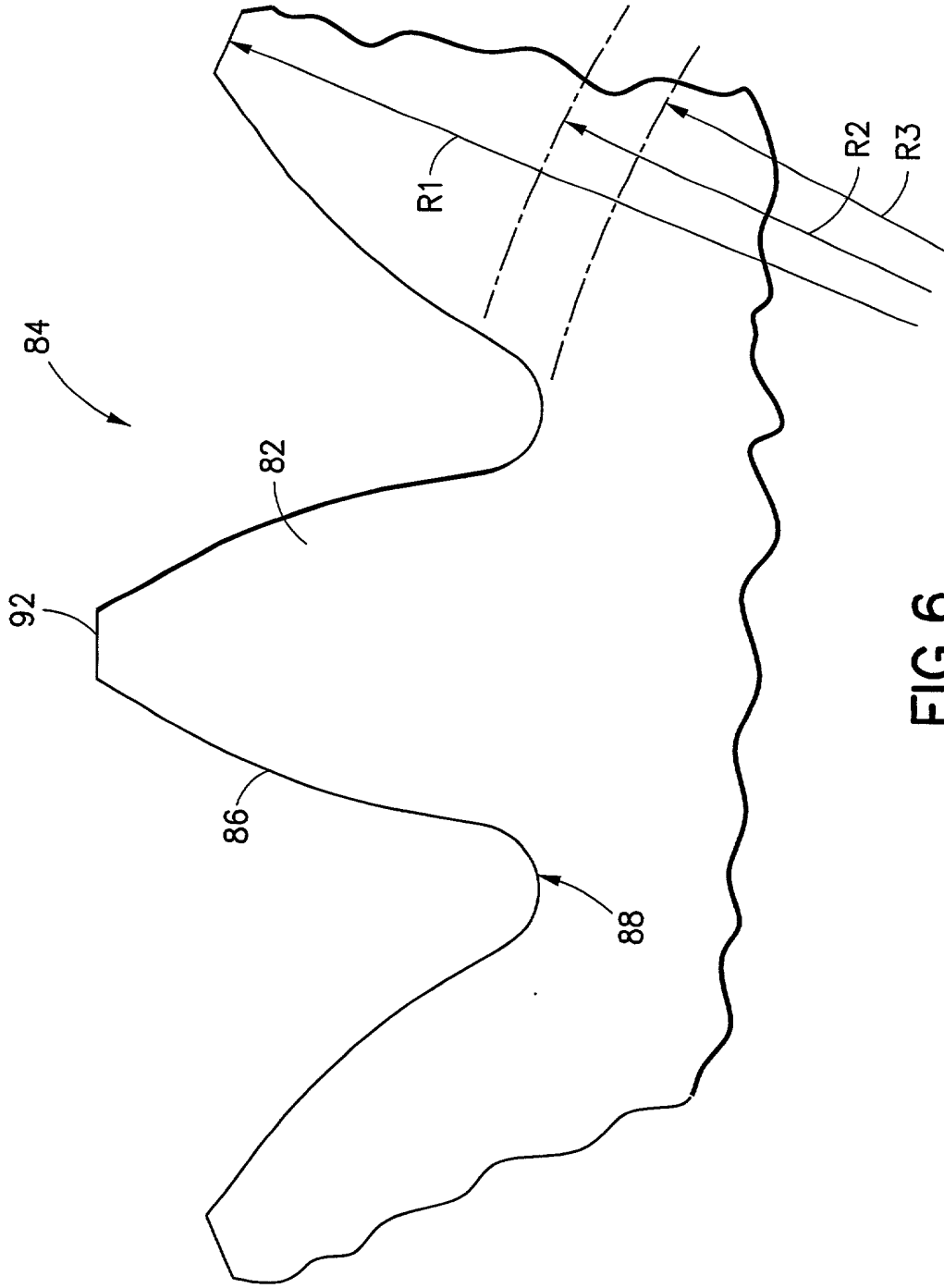


FIG. 6

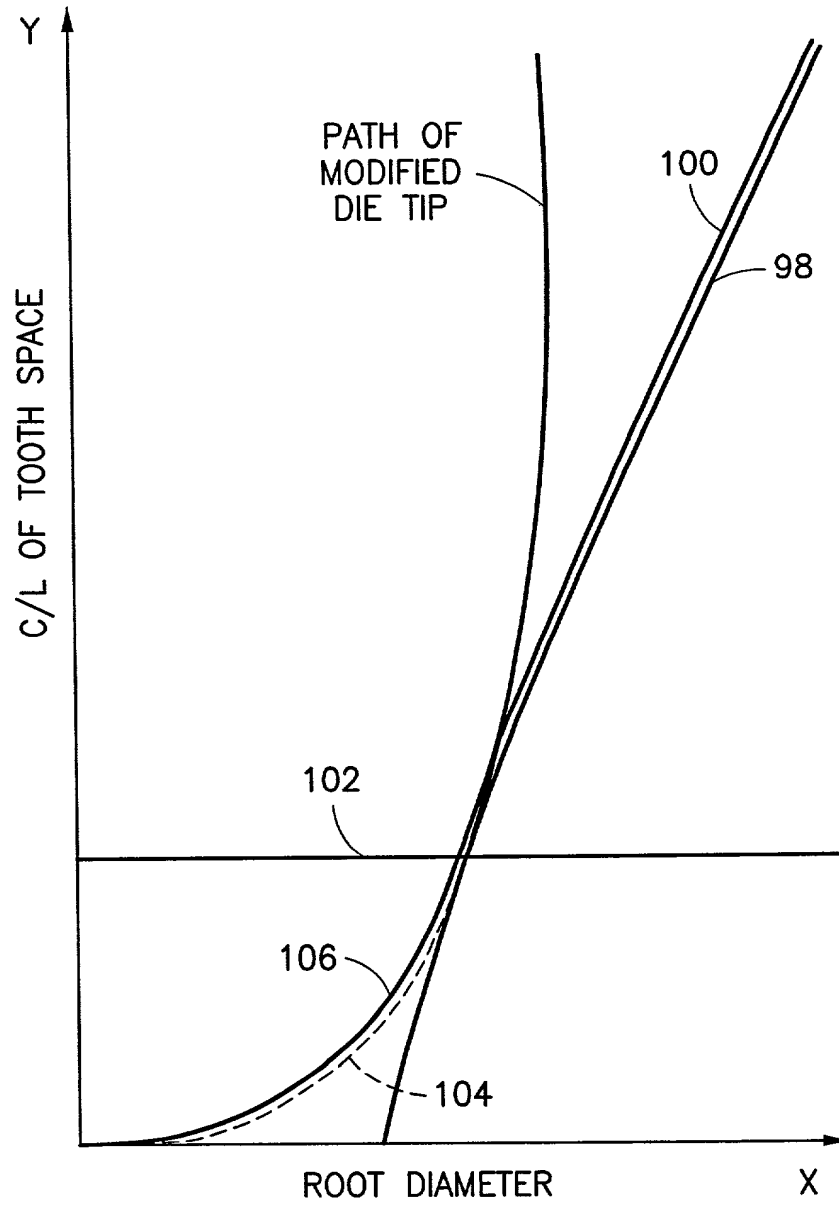


FIG.7

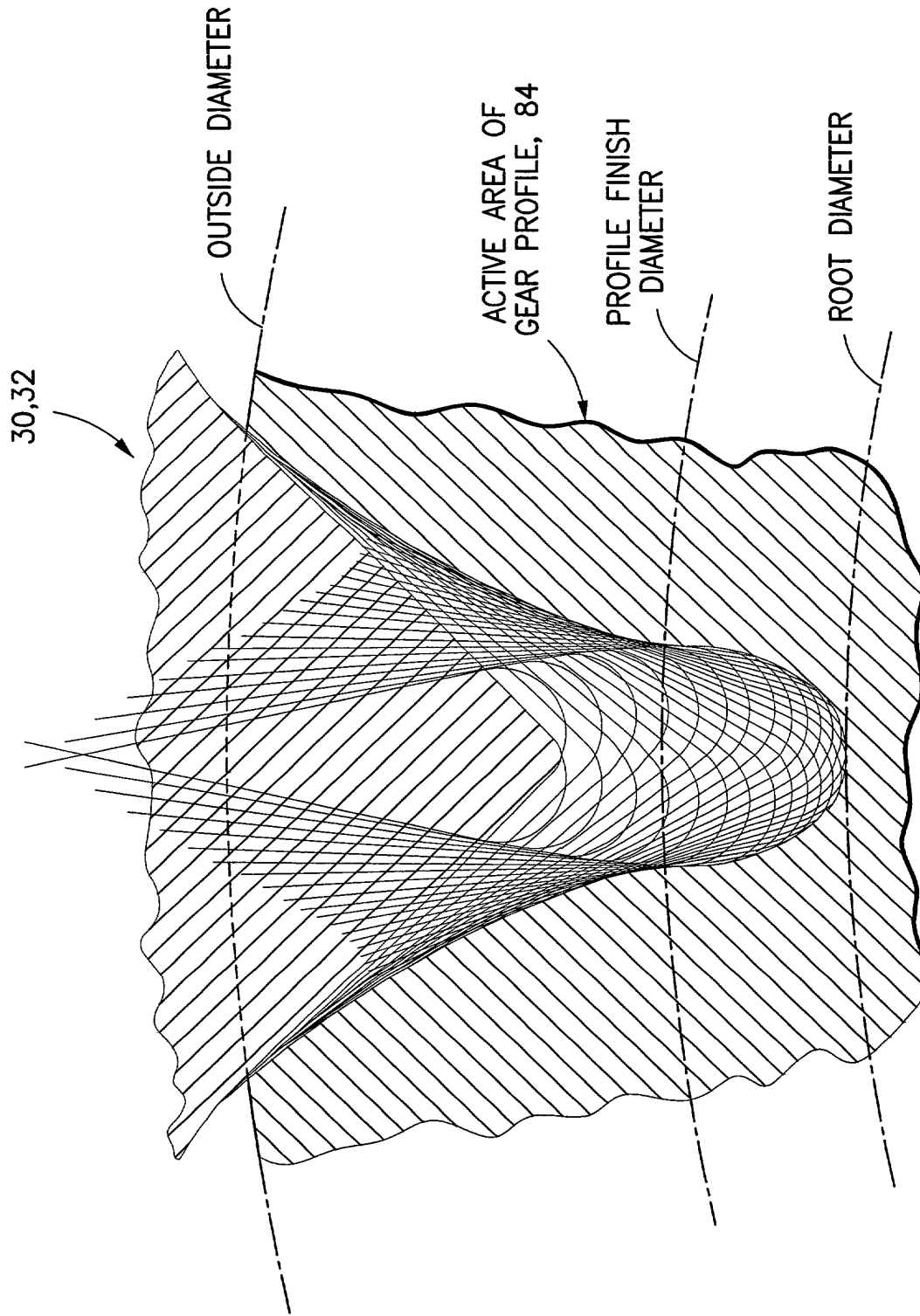


FIG.8

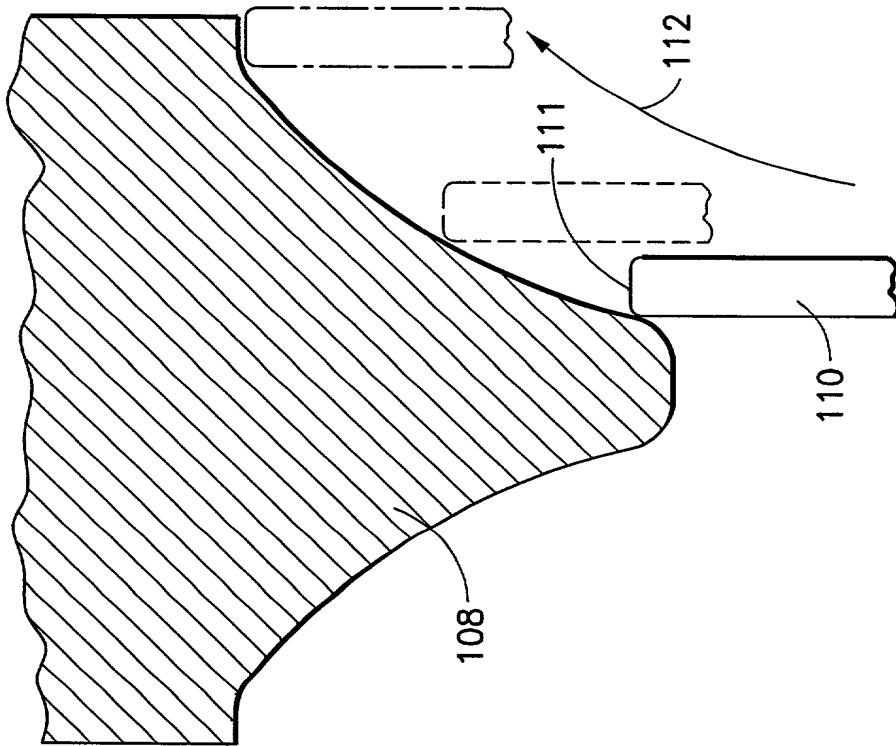


FIG. 9

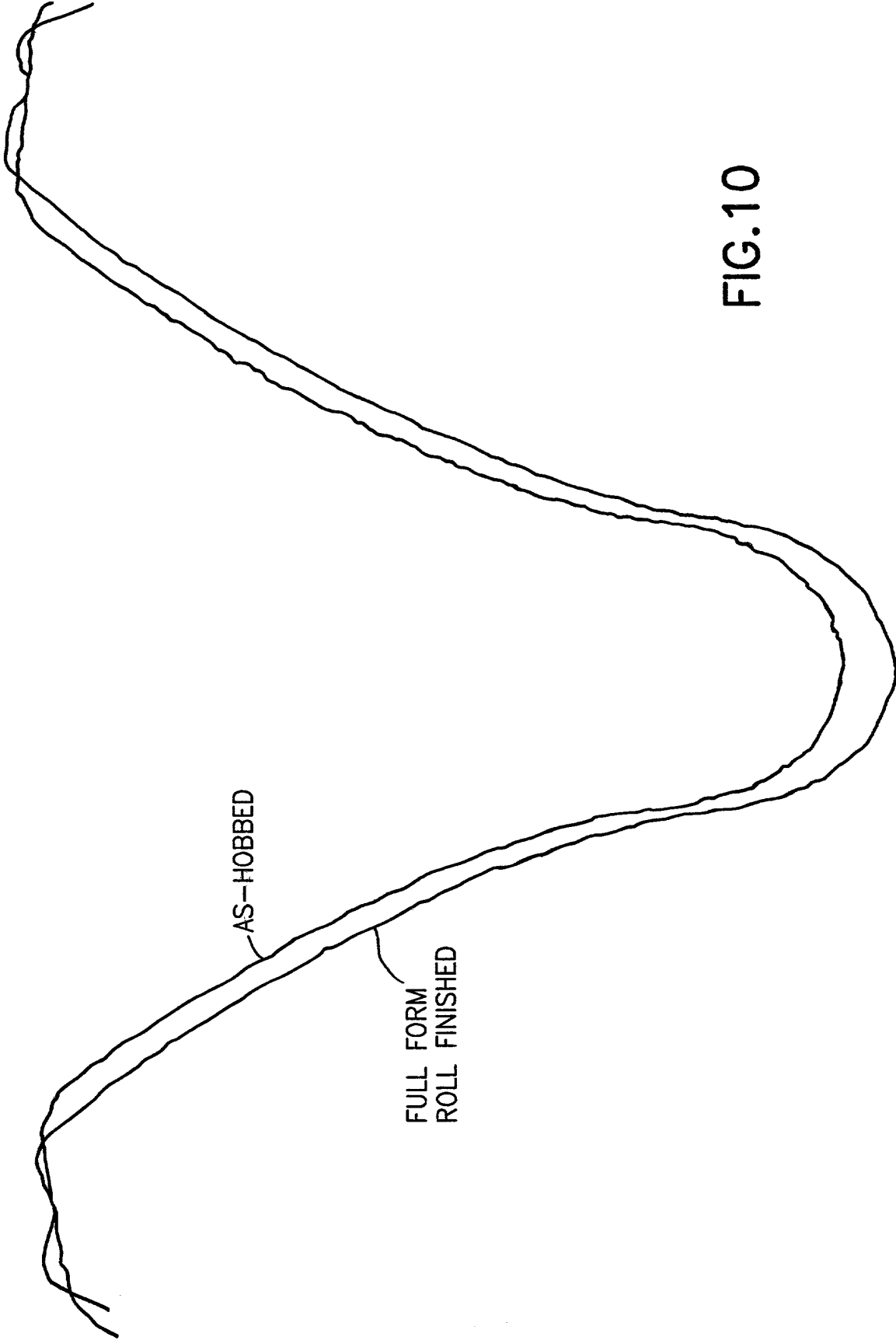


FIG. 10